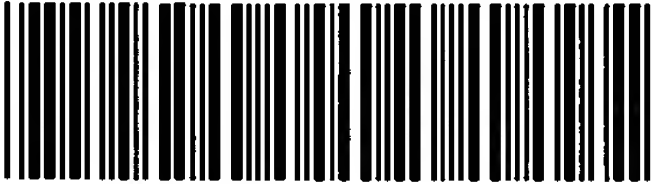


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/626,369	CHENG ET AL.	
	Examiner	Art Unit	
	Anthony Weier	1761	

SEARCHED			
Class	Subclass	Date	Examiner
updated	previous search	11/22/2005	AW

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR